DS05-11149-1E

MB8508S064CG-100/-100L

168-pin, 4 Clock, 1-bank, based on 8 M \times 8 Bit SDRAMs with SPD

DESCRIPTION

The Fujitsu MB8508S064CG is a fully decoded, CMOS Synchronous Dynamic Random Access Memory (SDRAM) Module consisting of eight MB81F64842C devices which organized as four banks of 8 M \times 8 bits and a 2K-bit serial EEPROM on a 168-pin glass-epoxy substrate.

The MB8508S064CG features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence.

The MB8508S064CG is optimized for those applications requiring high speed, high performance and large memory storage, and high density memory organizations.

This module is ideally suited for workstations, PCs, laser printers, and other applications where a simple interface is needed.

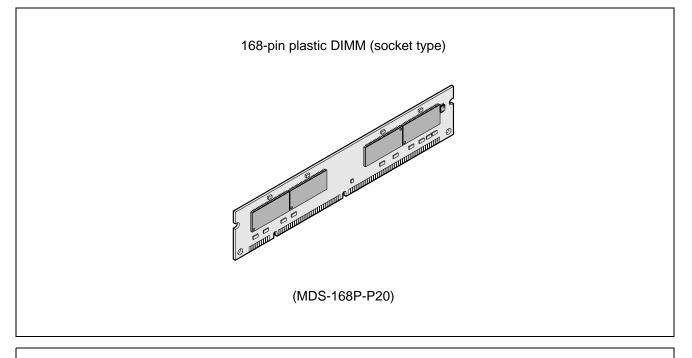
PRODUCT LINE & FEATURES

Parameter	MB8508S064CG					
Farameter	-100	-100L				
Clock Frequency	100 MHz max.					
Burst Mode Cycle Time	10 ns min.					
Access Time from Clock	8.5 ns max. (CL = 3)					
Operating Current	680 m	A max.				
Power Down Mode Current (Icc2P)	16 mA max.	8 mA max.				
Self Refresh Current (Icc6)	8 mA max.	4 mA max.				

- Unbuffered 168-pin DIMM Socket Type (Lead pitch: 1.27 mm)
- Conformed to JEDEC Standard (4 CLK)
- Organization: 8,388,608 words × 64 bits
- Memory: MB81F64842C (8 M \times 8, 4-bank) \times 8 pcs.
- 3.3 V ±0.3 V Supply Voltage
- All input/output LVTTL compatible
- 4096 Refresh Cycle every 65.6 ms

- Auto and Self Refresh
- CKE Power Down Mode
- DQM Byte Masking (Read/Write)
- Serial Presence Detect (SPD) with Serial EEPROM: JEDEC Standard SPD Format
- Module size:
- 1.0" (height) \times 5.25" (length) \times 0.157" (thickness)
- CL-trcd-trp: 3-3-3 clk min. @100 MHz,
 - 2-2-2 clk min. @66 MHz

■ PACKAGE

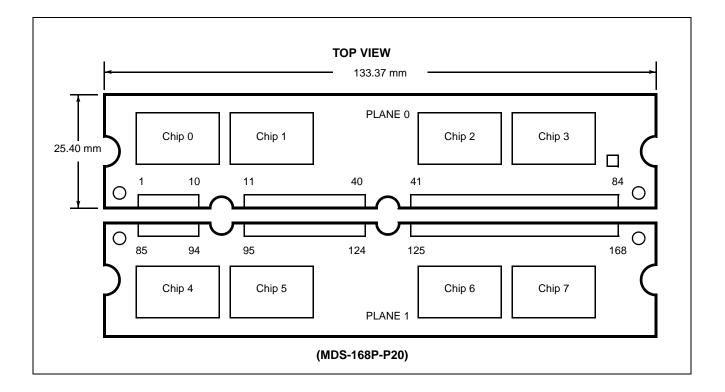


Package and Ordering Information

 - 168-pin DIMM, order as MB8508S064CG-100DG (DG = Gold Pad) MB8508S064CG-100LDG (LDG = Low power ver., Gold Pad)

■ PIN ASSIGNMENTS

Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name
1	Vss	29	DQMB ₁	57	DQ18	85	Vss	113	DQMB₅	141	DQ ₅₀
2	DQ ₀	30		58	DQ19	86	DQ32	114	N.C.	142	DQ ₅₁
3	DQ ₁	31	N.C.	59	Vcc	87	DQ33	115	RAS	143	Vcc
4	DQ ₂	32	Vss	60	DQ20	88	DQ ₃₄	116	Vss	144	DQ ₅₂
5	DQ ₃	33	Ao	61	N.C.	89	DQ35	117	A1	145	N.C.
6	Vcc	34	A2	62	N.C.	90	Vcc	118	Аз	146	N.C.
7	DQ4	35	A4	63	N.C.	91	DQ ₃₆	119	A5	147	N.C.
8	DQ₅	36	A ₆	64	Vss	92	DQ37	120	A7	148	Vss
9	DQ ₆	37	A8	65	DQ ₂₁	93	DQ38	121	A9	149	DQ ₅₃
10	DQ7	38	A10	66	DQ22	94	DQ39	122	BA ₀	150	DQ ₅₄
11	DQ8	39	BA1	67	DQ23	95	DQ40	123	A11	151	DQ55
12	Vss	40	Vcc	68	Vss	96	Vss	124	Vcc	152	Vss
13	DQ9	41	Vcc	69	DQ24	97	DQ ₄₁	125	CLK1	153	DQ56
14	DQ10	42	CLK ₀	70	DQ25	98	DQ42	126	N.C.	154	DQ ₅₇
15	DQ11	43	Vss	71	DQ ₂₆	99	DQ43	127	Vss	155	DQ ₅₈
16	DQ12	44	N.C.	72	DQ27	100	DQ44	128	CKE ₀	156	DQ59
17	DQ13	45	\overline{CS}_2	73	Vcc	101	DQ45	129	N.C.	157	Vcc
18	Vcc	46	DQMB ₂	74	DQ ₂₈	102	Vcc	130	DQMB ₆	158	DQ60
19	DQ14	47	DQMB ₃	75	DQ29	103	DQ ₄₆	131	DQMB7	159	DQ ₆₁
20	DQ15	48	N.C.	76	DQ30	104	DQ ₄₇	132	N.C.	160	DQ ₆₂
21	N.C.	49	Vcc	77	DQ ₃₁	105	N.C.	133	Vcc	161	DQ ₆₃
22	N.C.	50	N.C.	78	Vss	106	N.C.	134	N.C.	162	Vss
23	Vss	51	N.C.	79	CLK ₂	107	Vss	135	N.C.	163	CLK ₃
24	N.C.	52	N.C.	80	N.C.	108	N.C.	136	N.C.	164	N.C.
25	N.C.	53	N.C.	81	N.C.	109	N.C.	137	N.C.	165	SA ₀
26	Vcc	54	Vss	82	SDA	110	Vcc	138	Vss	166	SA1
27	WE	55	DQ ₁₆	83	SCL	111	CAS	139	DQ48	167	SA ₂
28	DQMB ₀	56	DQ17	84	Vcc	112	DQMB ₄	140	DQ49	168	Vcc



■ PIN DESCRIPTIONS

Symbol	I/O	Function	Symbol	I/O	Function
A ₀ to A ₁₁ , BA ₀ , BA ₁	I	Address Input	DQ ₀ to DQ ₆₃	I/O	Data Input/Data Output
RAS	I	Row Address Strobe	Vcc	_	Power Supply (+3.3 V)
CAS	I	Column Address Strobe	Vss	_	Ground (0 V)
WE	Ι	Write Enable	N.C.		No Connection
DQMB ₀ to DQMB ₇	I	Data (DQ) Mask	SA ₀ to SA ₂	I	Serial PD Address Input
CLK ₀ to CLK ₃	I	Clock Input	SCL	I	Serial PD Clock
CKE₀	I	Clock Enable	SDA	I/O	Serial PD Address/Data Input/Output
$\overline{CS}_0, \overline{CS}_2$	I	Chip Select			

■ SERIAL-PD INFORMATION

Function Described Defines Number of Bytes Written into Serial Memory at Module Manufacture Total Number of Bytes of SPD Memory Device Fundamental Memory Type Number of Row Addresses Number of Column Addresses Number of Module Banks Data Width Data Width Data Width (Continuation) Interface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency) DIMM Configuration Type	128 Byte 256 Byte SDRAM 12 9 1 bank 64 bit +0 LVTTL 10 ns	-100/100L 80h 08h 04h 0Ch 09h 01h 40h 00h
Serial Memory at Module Manufacture Total Number of Bytes of SPD Memory Device Fundamental Memory Type Number of Row Addresses Number of Column Addresses Number of Module Banks Data Width Data Width Data Width (Continuation) Interface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	256 Byte SDRAM 12 9 1 bank 64 bit +0 LVTTL	08h 04h 0Ch 09h 01h 40h
Total Number of Bytes of SPD Memory Device Fundamental Memory Type Number of Row Addresses Number of Column Addresses Number of Module Banks Data Width Data Width Data Width (Continuation) Interface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	SDRÅM 12 9 1 bank 64 bit +0 LVTTL	04h 0Ch 09h 01h 40h
Fundamental Memory Type Number of Row Addresses Number of Column Addresses Number of Module Banks Data Width Data Width (Continuation) nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	SDRÅM 12 9 1 bank 64 bit +0 LVTTL	04h 0Ch 09h 01h 40h
Number of Row Addresses Number of Column Addresses Number of Module Banks Data Width Data Width (Continuation) nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	12 9 1 bank 64 bit +0 LVTTL	0Ch 09h 01h 40h
Number of Column Addresses Number of Module Banks Data Width Data Width (Continuation) nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	9 1 bank 64 bit +0 LVTTL	09h 01h 40h
Number of Module Banks Data Width Data Width (Continuation) nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	1 bank 64 bit +0 LVTTL	01h 40h
Data Width Data Width (Continuation) nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	64 bit +0 LVTTL	40h
Data Width (Continuation) nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	+0 LVTTL	
nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)	LVTTL	00h
nterface Type SDRAM Cycle Time (Highest CAS Latency) SDRAM Access from Clock (Highest CAS Latency)		
SDRAM Access from Clock (Highest CAS Latency)	10 ns	01h
	10115	A0h
	8.5 ns	85h
	Non-Parity	00h
Refresh Rate/Type	Self, Normal	80h
Primary SDRAM Width	×8	08h
Error Checking SDRAM Width	0	00h
Ainimum Clock Delay for Back to Back Random Column	1 Cycle	01h
Addresses	- ,	
Burst Lengths Supported	1, 2, 4, 8, Page	8Fh
Number of Banks on Each SDRAM Device	4 bank	04h
CAS Latency	2, 3	06h
CS Latency	0	01h
Vrite Latency	0	01h
SDRAM Module Attributes	UN-buffer	00h
SDRAM Device Attributes	*1	0Eh
	15 ns	F0h
		90h
		00h
		00h
		1Eh
		14h
		1Eh
		3Ch
		10h
		00h
	1	01h
		57h
	<u> </u>	00h
		00h
	66MH7	66h
		CFh
ntel specification Details for 66MHz Support	<u> </u>	
888/88/J82//	DRAM Cycle Time (2nd. Highest CAS Latency) DRAM Access from Clock (2nd. Highest CAS Latency) DRAM Cycle Time (3rd. Highest CAS Latency) DRAM Access from Clock (3rd. Highest CAS Latency) linimum Row Precharge Time (tRP) <u>ow Activate</u> to Row Activate Min. (tRD) AS to CAS Delay Min. (tRCD) linimum RAS Pulse Width lodule Bank Density nused Storage Locations PD Data Revision Code hecksum for Byte 0 to 62 lanufacturer's Information: Unused Storage endor Specific Data: Unused Storage tel specification Frequency ttel specification Details for 66MHz Support nused Storage Locations	DRAM Access from Clock (2nd. Highest CAS Latency)9 nsDRAM Cycle Time (3rd. Highest CAS Latency)No SupportDRAM Access from Clock (3rd. Highest CAS Latency)No SupportDRAM Access from Clock (3rd. Highest CAS Latency)30 nsInimum Row Precharge Time (tRP)30 nsow Activate to Row Activate Min. (tRCD)30 nsAS to CAS Delay Min. (tRCD)30 nsInimum RAS Pulse Width60 nsIodule Bank Density64 MBytenused Storage LocationsPD Data Revision Code1hecksum for Byte 0 to 62*2lanufacturer's Information: Unused Storageendor Specific Data: Unused Storagetel specification Frequency66MHztel specification Details for 66MHz SupportCL=2, 3

Note: Any write operation must NOT be executed into the addresses of Byte 0 to Byte 127. Some or all data stored into Byte 0 to Byte 127 may be broken.

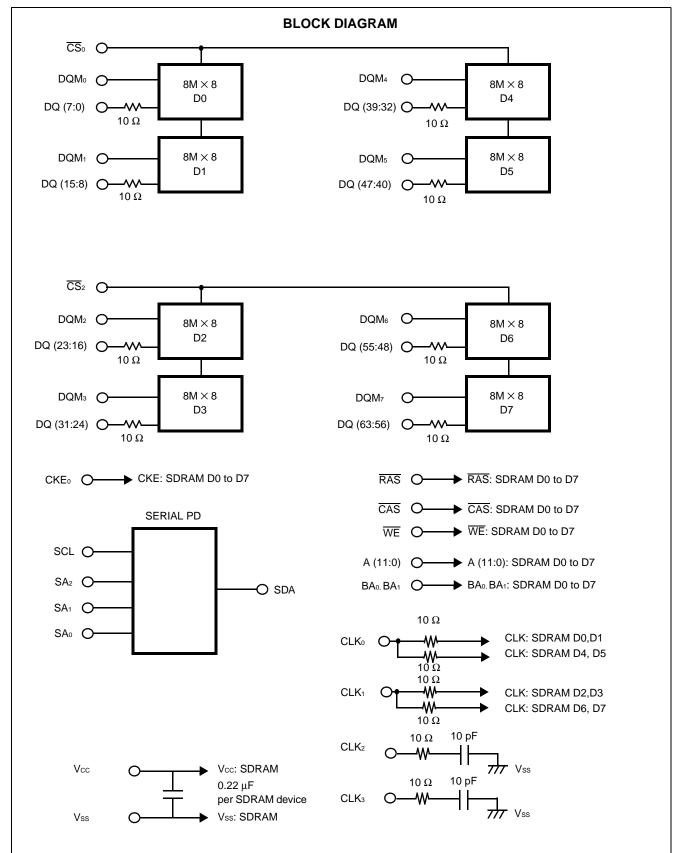
*1. Byte 22: SDRAM Device Attributes

Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
TBD	TBD	Upper Vcc tolerance	Lower Vcc tolerance	Supports Write 1 /Read Burst	Supports Precharge All	Supports Auto- precharge	Supports Early RAS Precharge
0	0	0	0	1	1	1	0

*2. Byte 63: Checksum for Bytes 0 to 62

This byte is the checksum for bytes 0 through 62. This byte contains the value of the low 8-bits of the arithmetic sum of bytes 0 through 62.

BLOCK DIAGRAM



■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

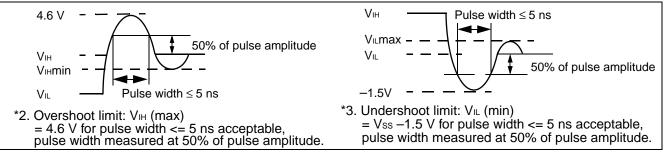
Peromotor	Symbol	Va	lue	Unit
Parameter	Symbol	Min.	Max.	Unit
Supply Voltage*	Vcc	-0.5	+4.6	V
Input Voltage*	VIN	-0.5	+4.6	V
Output Voltage*	Vout	-0.5	+4.6	V
Storage Temperature	Тѕтс	-55	+125	°C
Power Dissipation	PD	—	8.0	W
Output Current (D.C.)	Ιουτ	-50	+50	mA

* : Voltages referenced to Vss (= 0 V)

RECOMMENDED OPERATING CONDITIONS

Parameter	Notes	Symbol		Unit		
Farameter	NOLES	Symbol	Min.	Тур.	Max.	Onit
Supply Voltage	*1	Vcc	3.0	3.3	3.6	V
Supply voltage	1	Vss	0	0	0	V
Input High Voltage, All Inputs	*1, 2	Vін	2.0	—	Vcc +0.5	V
Input Low Voltage, All Inputs	*1, 3	VIL	-0.5	—	0.8	V
Ambient Temperature		TA	0		+70	°C

*1. Voltages referenced to Vss (= 0 V)



WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating conditionranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

■ CAPACITANCE

(Vcc = +3.3 V, f = 1 MHz, T _A = +25								
Parame	tor	Symbol	Va	lue	Unit			
Falalie		Symbol	Min.	Max.	Onit			
	Ao to A11, BAo, BA1	CIN1	_	67	pF			
	RAS, CAS, WE	CIN2		56	pF			
	$\overline{CS}_{0}, \overline{CS}_{2}$	Сімз		32	pF			
Input Canaditanaa	CKE	CIN4		58	pF			
Input Capacitance	CLK ₀ to CLK ₃	CIN5		41	pF			
	DQMB ₀ to DQMB ₇	CIN6		17	pF			
	SCL	CSCL		7	pF			
	SA0, SA1, SA2	CSA		9	pF			
	SDA	Csda		8	pF			
Input/Output Capacitance	DQ ₀ to DQ ₆₃	CDQ		13	pF			

■ DC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

					Value		
Parameter	Notes	Symbol	Condition	Min	M	ax.	Unit
				Min.	Std. ver.	Low ver.	
Operating Current (Average Power Supply Current)	*3	Icc1s	Burst: Length = 1 t_{RC} = min for BL = 1 t_{CK} = min One Bank Active, Outputs Open Addresses changed up to 1-time during t_{CK} (min.) $0 V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$	_	6	80	mA
		Ісс2р	$\begin{array}{l} CKE = V_{\text{IL}}, All \; Banks \; Idle \\ t_{CK} = min, Power \; Down \; Mode \\ 0 \; V \leq V_{IN} \leq V_{IL} \; (max.) \\ V_{IH} \; (min.) \leq V_{IN} \leq V_{CC} \end{array}$		16	8	mA
Precharge Standby Current (Power Supply Current)		Icc2ps	$\begin{array}{l} CKE = V_{IL}, All \; Banks \; Idle \\ CLK = H \; or \; L, \; Power \; Down \; Mode \\ 0 \; V \leq V_{IN} \leq V_{IL} \; (max.) \\ V_{IH} \; (min.) \leq V_{IN} \leq V_{CC} \end{array}$	_	8	4	mA
	*3	Icc2n	$\begin{array}{l} CKE=V_{IH}, All \; Banks \; Idle, t_{CK}=min \\ NOP \; commands \; only, Input \; signals \\ (except \; to \; CMD) \; are \; changed \; 1\text{-time} \\ during \; 3 \; clock \; cycles \\ 0 \; V \leq V_{IN} \leq V_{IL} \; (max.) \\ V_{IH} \; (min.) \leq V_{IN} \leq V_{CC} \end{array}$		8	30	mA
		Ісс2№	$\begin{array}{l} CKE=V_{IH},All\;Banks\;Idle\\ CLK=H\;or\;L,Input\;signal\;are\;stable\\ 0\;V\leqV_{IN}\leqV_{IL}\;(max.)\\ V_{IH}\;(min.)\leqV_{IN}\leqV_{CC} \end{array}$		1	6	mA
		Іссзр	$\begin{array}{l} CKE = V_{IL}, Any \ Bank \ Active \\ tck = min. \\ 0 \ V \leq V_{IN} \leq V_{IL} \left(max.\right) \\ V_{IH} \left(min.\right) \leq V_{IN} \leq V_{Cc} \end{array}$	_	16	8	mA
Activo Standby		Іссзря	$\begin{array}{l} CKE = V_{IL}, Any Bank Active \\ CLK = H or L \\ 0 V \leq V_{IN} \leq V_{IL} (max.) \\ V_{IH} (min.) \leq V_{IN} \leq V_{CC} \end{array}$		8	4	mA
Active Standby Current (Power Supply Current)	*3	Іссзи	$\begin{array}{l} CKE = V_{IH}, Any Bank Active \\ t_{CK} = min., NOP commands only, Input \\ signals (except to CMD) are changed \\ 1\text{-time} during 3 clock cycles \\ 0 V \leq V_{IN} \leq V_{IL} (max.) \\ V_{IH} (min.) \leq V_{IN} \leq V_{CC} \end{array}$		1.	20	mA
		Іссзия	$\begin{array}{l} CKE = V_{IH}, Any Bank Active \\ CLK = H or L \\ 0 V \leq V_{IN} \leq V_{IL} (max.) \\ V_{IH} (min.) \leq V_{IN} \leq V_{CC} \end{array}$	—	1	6	mA

(Continued)

(Continued)

					Value			
Parameter N	Notes	tes Symbol Condition		Min.	Ma	Unit		
				IVIIII.	Std. ver.	Low ver.		
Burst Mode Current (Average Power Supply Current)	*3	Icc4	$\begin{array}{l} t_{CK} = min, \ Burst \ Length = 4 \\ Outputs \ Open, \ All \ Banks \ Active \\ Gapless \ Data \\ 0 \ V \leq V_{IN} \leq V_{IL} \ (max.) \\ V_{IH} \ (min.) \leq V_{IN} \leq V_{CC} \end{array}$		4	30	mA	
Auto-refresh Current (Average Power Supply Current)	*3	Icc5	Auto Refresh tck = min tRc = min $0 V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$		1360		mA	
Self-refresh Current (Average Power Supply Current)	*3	Icc6	$\begin{array}{l} \text{Self-Refresh} \\ t_{CK} = \min. \\ \text{CKE} \leq 0.2 \text{ V} \\ 0 \text{ V} \leq V_{\text{IN}} \leq V_{\text{IL}} (\text{max.}) \\ \text{V}_{\text{IH}} (\text{min.}) \leq V_{\text{IN}} \leq V_{\text{CC}} \end{array}$	_	8	4	mA	
Input Leakage Current (All Inputs)		II (L)	$0 V \le V_{IN} \le V_{CC}$ All other pins not under test = 0 V	-30	3	0	μA	
Output Leakage Currer	nt	lo (L)	$0 V \le V_{IN} \le V_{CC}$ Output is disabled (Hi-Z)	-10	10		μΑ	
LVTTL Output High Voltage	*4	Vон	Іон = -2.0 mA	2.4	-	_	V	
LVTTL Output Low Voltage	*4	Vol	lo∟ = +2.0 mA	_	0	.4	V	

Notes: *1. An initial pause (DESL on NOP) of 200 μs is required after power-on followed by a minimum of eight Auto-refresh cycles.

*2. DC characteristics is the Serial PD standby state (VIN = Vss or Vcc).

*3. Icc depends on the output termination, load conditions, clock cycle rate and signal clock rate. The specified values are obtained with the output open and no termination register.

*4. Voltages referenced to $V_{SS} = V_{SSQ} (= 0 V)$.

■ AC CHARACTERISTICS

(1) BASE CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2, 3

No.	Parameter Notes	Notes		MB8508S064CG -100/100L		Unit
			Symbol	Min.	Max.	
1	Clock Period	CL = 3	t скз	10	—	ns
	Clock Fellou	CL = 2	tск2	15	—	ns
2	Clock High Time		tсн	3.5	—	ns
3	Clock Low Time		tc∟	3.5	—	ns
4	Input Setup Time	tsı	3	_	ns	
5	Input Hold Time	tнı	1	—	ns	
6	Output Valid from Clock *4, *	CL = 3	tасз	—	8.5	
0	$(t_{CLK} = min)$ 4,	CL = 2	t _{AC2}	—	9	ns
7	Output in Low-Z	6	t∟z	0	—	ns
8	Output in High-Z	6 CL = 3	t HZ3	3	8.5	ns
0		CL = 2	tHZ2	3	9	ns
9	Output Hold Time	6	tон	3	—	ns
10	Time between Refresh		tref	—	65.6	ms
11	Transition Time		t⊤	0.5	2	ns
12	CKE Setup Time for Power Down Exit Tim	e	t cksp	3		ns

(2) BASE VALUES FOR CLOCK COUNT/LATENCY

No.	Parameter Notes	Symbol	MB8508 -100/	Unit		
				Min.	Max.	
1	RAS Cycle Time *7	t RC	90	—	ns	
2	RAS Precharge Time	t RP	30	_	ns	
3	RAS Active Time	tras	60	110000	ns	
4	RAS to CAS Delay Time *8	trcd	30	—	ns	
5	Write Recovery Time		twr	10	_	ns
6	RAS to RAS Bank Active Delay Time		t RRD	20		ns
7	Data-in to Precharge Lead Time		t dpl	10	_	ns
8	Data-in to Active/Refresh Command Period	CL = 3	tdal3	2 cyc + t _{RP}	_	ns
8	Data-in to Active/Reliesh Command Period	CL = 2	tDAL2	1 cyc + t _{RP}		ns
9	Mode Register Set Cycle Time	trsc	20		ns	

(3) CLOCK COUNT FORMULA (*9)

 $Clock \ge \frac{Base Value}{Clock Period}$ (Round off a whole number)

(4) LATENCY (The latency values on these parameters are fixed regardless of clock period.)

No.	Parameter	Symbol	MB8508S064CG -100/100L	Unit	
1	CKE to Clock Disable		Іске	1	Cycle
2	DQM to Output in High-Z		Idqz	2	Cycle
3	DQM to Input Data Delay		IDQD	0	Cycle
4	Last Output to Write Command Delay		lowd	2	Cycle
5	Write Command to Input Data Delay		lowd	0	Cycle
6	Procharge to Output in High 7 Delay	CL = 3	Ігонз	3	Cycle
	Precharge to Output in High-Z Delay	CL = 2	IROH2	2	Cycle
7	Rurat Stop Command to Output in High 7 Delay	CL = 3	Івѕнз	3	Cycle
	Burst Stop Command to Output in High-Z Delay	CL = 2	IBSH2	2	Cycle
8	CAS to CAS Delay (min)		Ісср	1	Cycle
9	CAS Bank Delay (min)		Ісвр	1	Cycle

Notes: *1. An initial pause (DESL on NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.

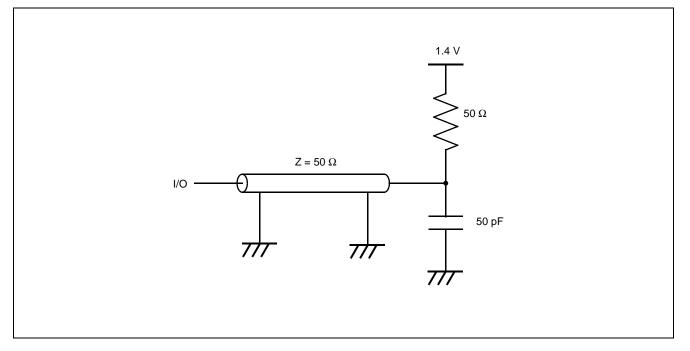
- *2. 1.4 V or V_{REF} is the reference level for measuring timing of signals. Transition times are measured between V_{IH} (min) and V_{IL} (max).
- *3. AC characteristics assume $t_T = 1$ ns and 50 pF of capacitive load.
- *4. Maximum value of CL = 2 depends on tck.
- *5. tac also specifies the access time at burst mode except for first access.
- *6. Specified where output buffer is no longer driven. toн, tLz, and tHz define the times at which the output level achieves ±200 mV.
- *7. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
- *8. Operation within the tRCD (min) ensures that access time is determined by tRCD (min) + tAC (max); if tRCD is greater than the specified tRCD (min), access time is determined by tAC.
- *9. All base values are measured from the clock edge at the command input to the clock edge for the next command input.

All clock counts are calculated by a simple formula:

clock count equals base value divided by clock period (round off to a whole number).

*Source: See MB81F64842C Data Sheet for details on the electrical.





■ SERIAL PRESENCE DETECT(SPD) FUNCTION

1. PIN DESCRIPTIONS

SCL (Serial Clock)

SCL input is used to clock all data input/output of SPD

SDA (Serial Data)

SDA is a common pin used for all data input/output of SPD. The SDA pull-up resistor is required due to the open-drain output.

SA₀, SA₁, SA₂ (Address)

Address inputs are used to set the least significant three bits of the eight bits slave address. The address inputs must be fixed to select a particular module and the fixed address of each module must be different each other.

2. SPD OPERATIONS

CLOCK and DATA CONVENTION

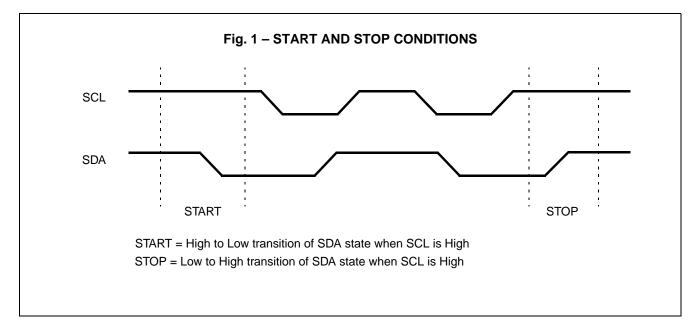
Data states on the SDA can change only during SCL = Low. SDA state changes during SCL = High are indicated start and stop conditions. Refer to Fig. 1 below.

START CONDITION

All commands are preceded by a start condition, which is a transition of SDA state from High to Low when SCL = High. SPD will not respond to any command until this condition has been met.

STOP CONDITION

All read or write operation must be terminated by a stop condition, which is a transition of SDA state from Low to High when SCL = High. The stop condition is also used to make the SPD into the state of standby power mode after a read sequence.



ACKNOWLEDGE

Acknowledge is a software convention used to indicate successful data transfer. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will put the SDA line to Low in order to acknowledge that it received the eight bits of data.

The SPD will respond with an acknowledge when it received the start condition followed by slave address issued by master.

In the read operation, the SPD will transmit eight bits of data, release the SDA line and monitor the line for an acknowledge. If an acknowledge is detected and no stop condition is issued by master, the SPD will continue to transmit data. If an acknowledge is not detected, the SPD will terminated further data transmissions. The master must then issue a stop condition to return the SPD to the standby power mode.

In the write operation, upon receipt of eight bits of data the SPD will respond with an acknowledge, and await the next eight bits of data, again responding with an acknowledge until the stop condition is issued by master.

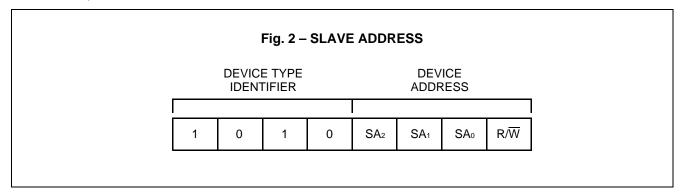
SLAVE ADDRESS ADDRESSING

Following a start condition, the master must output the eight bits slave address. The most significant four bits of the slave address are device type identifier. For the SPD this is fixed as 1010[B]. Refer to the Fig. 2 below.

The next three significant bits are used to select a particular device. A system could have up to eight SPD devices —namely up to eight modules— on the bus. The eight addresses for eight SPD devices are defined by the state of the SA₀, SA₁ and SA₂ inputs.

The last bit of the slave address defines the operation to be performed. When R/\overline{W} bit is "1", a read operation is selected, when R/\overline{W} bit is "0", a write operation is selected.

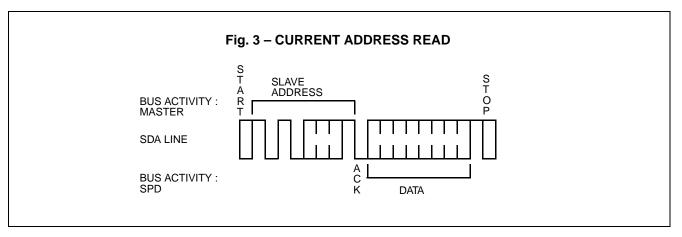
Following the start condition, the SPD monitors the SDA line comparing the slave address being transmitted with its slave address (device type and state of SA₀, SA₁, and SA₂ inputs). Upon a correct compare the SPD outputs an acknowledge on the SDA line. Depending on the state of the R/W bit, the SPD will execute a read or write operation.



3. READ OPERATIONS

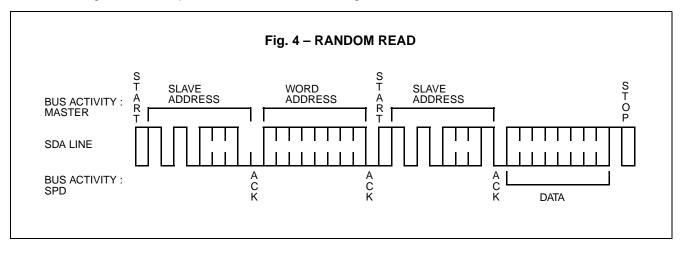
CURRENT ADDRESS READ

Internally the SPD contains an address counter that maintains the address of the last data accessed, incremented by one. Therefore, if the last access (either a read or write operation) was to address(n), the next read operation would access data from address(n+1). Upon receipt of the slave address with the R/W bit = "1", the SPD issues an acknowledge and transmits the eight bits of data during the next eight clock cycles. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 3 for the sequence of address, acknowledge and data transfer.



RANDOM READ

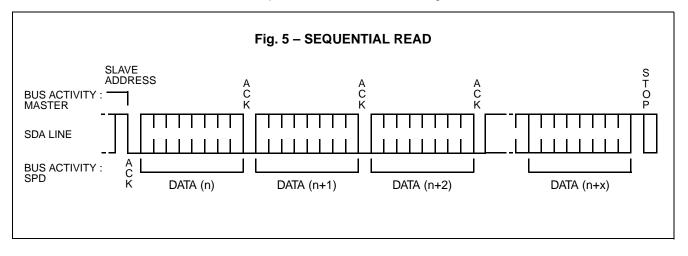
Random Read operations allow the master to access any memory location in a random manner. Prior to issuing the slave address with the R/W bit = "1", the master must first perform a "dummy" write operation on the SPD. The master issues the start condition, and the slave address followed by the word address. After the word address acknowledge, the master immediately reissues the start condition and the slave address with the R/W bit = "1". This will be followed by an acknowledge from the SPD and then by the eight bits of data. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 4 for the sequence of address, acknowledge and data transfer.



SEQUENTIAL READ

Sequential Read can be initiated as either a current address read or random read. The first data are transmitted as with the other read mode, however, the master now responds with an acknowledge, indicating it requires additional data. The SPD continues to output data for each acknowledge received. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 5 for the sequence of address, acknowledge and data transfer.

The data output is sequential, with the data from address(n) followed by the data from address(n+1). The address counter for read operations increments all address bits, allowing the entire memory contents to be serially read during one operation. At the end of the address space (address 255), the counter "rolls over" to address 0 and the SPD continues to output data for each acknowledge received.



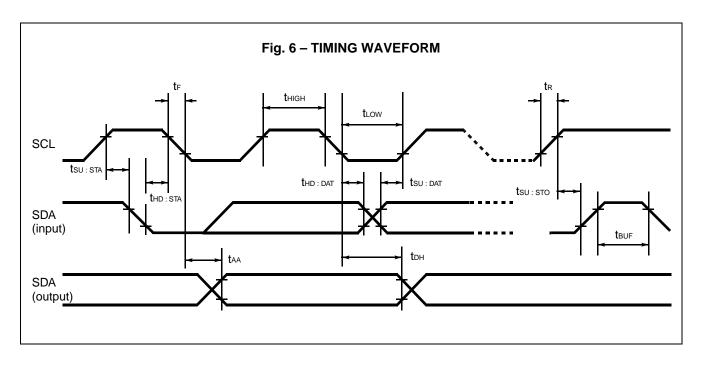
4. DC CHARACTERISTICS

Parameter	Note S	Symbol	Condition	Value		Unit
Farameter			Condition	Min.	Max.	Unit
Input Leakage Current		Sili	$0~V \leq V_{\text{IN}} \leq V_{\text{CC}}$	-10	10	μA
Output Leakage Current		SILO	$0 \text{ V} \leq \text{V}_{\text{OUT}} \leq \text{V}_{\text{CC}}$	-10	10	μA
Output Low Voltage	*1	Svol	lo∟ = 3.0 mA	—	0.4	V

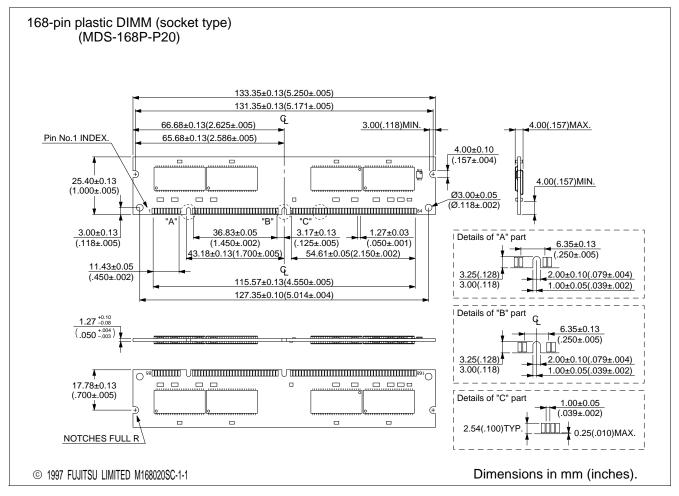
Note: *1. Referenced to Vss.

5. AC CHARACTERISTICS

No.	Parameter	Symbol	Value		Unit
INO.		Symbol	Min.	Max.	Onit
1	SCL Clock Frequency	fsc∟	—	100	KHz
2	Noise Suppression Time Constant at SCL, SDA Inputs	Тı	_	100	ns
3	SCL Low to SDA Data Out Valid	taa	—	3.5	μs
4	Time the Bus Must Be Free Before a New Transmission Can Start	tBUF	4.7	—	μs
5	Start Condition Hold Time	thd:sta	4.0	—	μs
6	Clock Low Period	t∟ow	4.7		μs
7	Clock High Period	tніgн	4.0		μs
8	Start Condition Setup Time	tsu:sta	4.7		μs
9	Data in Hold Time	thd:dat	0		μs
10	Data in Setup Time	tsu:dat	250		ns
11	SDA and SCL Rise Time	tr	_	1	μs
12	SDA and SCL Fall Time	t⊧	—	300	ns
13	Stop Condition Setup Time	tsu:sto	4.7	—	μs
14	Data Out Hold Time	tон	100	_	ns
15	Write Cycle Time	twr	_	15	ms



PACKAGE DIMENSION



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